

# IEEE MTT-S FRANCE CHAPTER AND IEEE IM-S CHAPTER DAY On Instrumentation and Measurements for Microwave and Millimeter-wave Applications

## CALL FOR PARTICIPATION

November 16<sup>th</sup>, 2017

University of Bordeaux, France

Services based on RF electronic devices, such as automotive radar, wireless backhaul and electro-optical networking, are increasingly pervading our daily life. Future applications like THz imaging, radar above 100 GHz, biomedical sensing, high-data rate space communication, 5G and IoT networking are expected to be deployed, enabled by recent development in silicon and III-V transistors process technologies, featuring millimeter-wave up to THz cut-off frequencies.

In this context, the objective of this IEEE MTT-S and IEEE IM-S day is to present new technologies and circuits' characterization targeting microwave and millimeter-wave applications, such as IoT and 5G applications.

The MTT & IM day includes :

- an invited EuMA DML talk: "Design of planar, SW & volumic miniature microwave filters for space applications", Prof E. Rius, *University of Bretagne*
- an invited IEEE IM DL: "Smart Tailored Environments for Neuro-Motor Rehabilitation Monitoring in IoT Era", O. Postolache, *University of Lisbon*
- a technical session with posters' presentation
- a demonstration on the IoT and a visit of the IMS laboratory characterization platform

For the posters' presentation, authors must submit a one or two page abstract in PDF format at: [tifenn.martin@u-bordeaux.fr](mailto:tifenn.martin@u-bordeaux.fr)

A price will be given for the best poster.

This event is part of conference BEE Week 2017. Registration is free of charge. More information : [www.ieee-bordeaux.org](http://www.ieee-bordeaux.org)



### Organizers

Tifenn Martin  
Camilo Coelho  
Marina Deng  
Dominique Dallet  
Anthony Ghiotto

### Important Dates

Abstract submission deadline:  
9th October 2017

Notification of acceptance:  
16th October 2017

